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- (71) Applicant: **RAMBUS INC.** [US/US]; 1050 Enterprise Way, Suite 700, Sunnyvale, CA 94089 (US).
- (72) Inventors: **GILL, Patrick R.**; 1050 Enterprise Way, Suite 700, Sunnyvale, CA 94089 (US). **STORK, David G.**; 1050 Enterprise Way, Suite 700, Sunnyvale, CA 94089 (US). **LINSTADT, John Eric**; 1050 Enterprise Way, Suite 700, Sunnyvale, CA 94089 (US).
- (74) Agent: **BEHIEL, Arthur J.**; Silicon Edge Law Group LLP, 7901 Stoneridge Drive, Suite 528, Pleasanton, CA 94588 (US).
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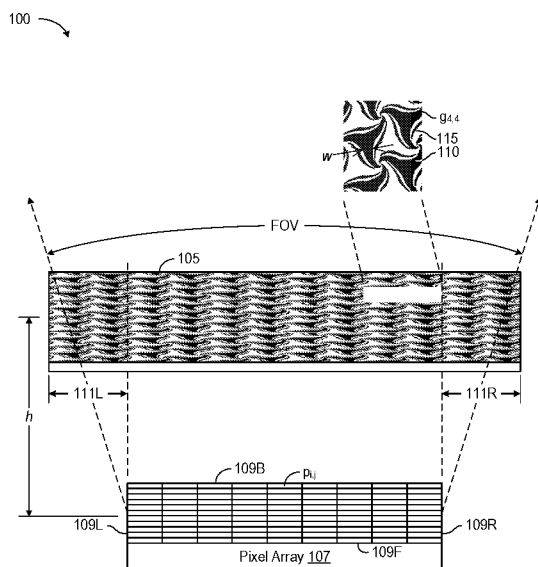


FIG. 1

(57) Abstract: An imaging system includes a phase grating overlying a two-dimensional array of pixels, which may be thermally sensitive pixels for use in infrared imaging. The phase grating comprises a two-dimensional array of identical subgratings that define a system of Cartesian coordinates. The subgrating and pixel arrays are sized and oriented such that the pixels are evenly distributed with respect to the row and column intersections of the subgratings. The location of each pixel thus maps to a unique location beneath a virtual archetypical subgrating. Portions of the phase grating extend beyond the edges of the pixels array to interference pattern in support of Fourier-domain imaging.



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Systems and Methods for Improving Resolution in Lensless Imaging

BACKGROUND

[0001] Focusing optics and related components contribute significantly to the cost and size of common imaging devices. The materials used in the manufacture of infrared (IR) lenses (e.g., monocrystalline Germanium) are particularly expensive, and the cost of IR lenses tends to scale with the cube of their linear size. As a result, IR imaging devices tend to be cost prohibitive.

BRIEF DESCRIPTION OF THE DRAWINGS

[0002] The detailed description is illustrated by way of example, and not by way of limitation, in the figures of the accompanying drawings and in which like reference numerals refer to similar elements and in which:

[0003] Figure 1 depicts an infrared (IR) imaging device 100 that employs a phase grating in lieu of a lens.

[0004] Figure 2 is a plan view of imaging device 100 of Figure 1.

[0005] Figure 3 shows IR imaging device 100 of Figures 1 and 2 with the full tessellation of subgratings $g_{i,j}$ that make up phase grating layer 105.

[0006] Figure 4 is a cut-away view of imaging device 100 of Figures 1-3.

[0007] Figure 5 depicts imaging device 100 with the details of subgratings $g_{i,j}$ obscured for ease of illustration.

[0008] Figure 6 depicts imaging device 100, again with the details of subgratings $g_{i,j}$ obscured for ease of illustration, with certain pixels shaded to illustrate their respective contributions.

[0009] Figure 7A depicts an imaging device 700 in accordance with another embodiment.

[0010] Figure 7B depicts imaging device 700 rotated by angle θ . Each subgrating $g_{i,j}$ is divided into nine equal regions using dashed lines.

[0011] Figure 8A depicts imaging device 700 of Figures 7A and 7B with the array of pixels $p_{i,j}$ oriented at angle θ relative to the array of subgratings $g_{i,j}$ as in the example of Figure 7B.

[0012] Figure 8B depicts the nine subgratings $g_{i,j}$ of imaging device 700 of Figure 8A separated and the pixel outlines omitted to highlight the unique constellations of pixel centers associated with each subgrating.

[0013] Figure 8C depicts an archetypal subgrating 860 encompassing all the constellations of pixel centers from the nine subgratings $g_{i,j}$ of e.g. Figures 8A and 8B.

[0014] Figure 9 depicts an imaging device 900 in accordance with another embodiment.

[0015] Figure 10 depicts imaging device 1000 similar to the device 900 of Figure 9 but reoriented such that the rows and columns of pixels 905 are horizontal and vertical in the view, as would be expected—though not necessary—for a camera of this type.

[0016] Figure 11 depicts an imaging device 1100 in accordance with another embodiment.

[0017] Figure 12 depicts imaging device 1100 of Figure 11 with subgratings 1110 trimmed around the perimeter.

[0018] Figure 13 depicts an imaging device 1300 in accordance with another embodiment.

[0019] Figure 14 depicts an imaging device 1400 in accordance with another embodiment.

DETAILED DESCRIPTION

[0020] Figure 1 depicts an infrared (IR) imaging device 100 that employs a phase grating in lieu of a lens. Employing a phase grating in lieu of a lens can dramatically reduce size and cost. Viewed from a perspective normal to the active surface, device 100 includes a phase grating layer 105 spaced by a height h above an array 107 of pixels $p_{i,j}$, where i and j refer to locations along the respective X and Y axes. Grating layer 105 includes a repeating pattern of subgratings $g_{i,j}$, of which one subgrating $g_{4,4}$ is shown from the normal perspective for ease of viewing; the remaining subgratings $g_{i,j}$ are identical in this example.

[0021] Pixel array 107 includes a first edge 109L, a second edge 109R, a third edge 109F, and a fourth edge 109B. Phase grating layer 105 includes left and right portions 111L and 111R that extend beyond the respective left and right edges of the underlying pixel array 107. Portions 111L and 111R are columns of subgratings that repeat the pattern of subgratings $g_{i,j}$ that extends over and between left and right edges 109L and 109R. Rows of repeating subgratings likewise extend beyond the respective front and back edges 109F and 109B of pixel array 107. The overlapping portions extend over the field of view FOV for imaging device 100.

[0022] Phase gratings of the type used for subgratings $g_{i,j}$ are detailed in U.S. Patent Application 14/677,878 to Stork et al, which is incorporated herein by this reference. Briefly, and in connection with subgrating $g_{4,4}$, subgratings $g_{i,j}$ are of a material that is transparent to IR light. The surface of subgratings $g_{i,j}$ includes transparent features 110 (black) and 115 (white) that define between them boundaries of odd symmetry. Features 110 are raised in the Z dimension (normal to the view) relative to features 115, and are shown in black to elucidate this topography. Features 110 and 115 form six-armed spiral shapes in this embodiment (the black and white features both contribute “arms” that contribute to the point-spread function of the grating). The width W of the thickest portion of the arms is about 120 microns. As detailed below, the boundaries between features 110 and 115 produce an interference pattern on the underlying pixel array that contains rich spatial information about an imaged scene. This spatial information can be processed using e.g. Fourier- or spatial-domain deconvolution to render photographs or identify features of interest in the imaged scene.

[0023] Fourier-domain image reconstruction implicitly assumes that the point-spread function of the imaged interference pattern wraps around at the edges of the pattern. The portions of grating array 105 that extend beyond the edges of pixel array 107 (e.g., portions 111L and 111R) extend the interference pattern in support of Fourier-domain strategies. Subgratings $g_{i,j}$ are tiled with copies along the borders of array 105 that extend out from pixel array 107 to cover all angles from which incident light is likely to strike array 107.

[0024] Figure 2 is a plan view of imaging device 100 of Figure 1. Of the repeating pattern of subgratings $g_{i,j}$, only subgrating $g_{4,4}$ is shown in detail; the remaining subgratings $g_{i,j}$ are identical in this example, and are highlighted using bold boundaries to show their placement, orientation, and size relative to underlying pixels $p_{i,j}$. Subgratings $g_{i,j}$ are rectangular in this embodiment, with a minimum dimension G_{px} in the x dimension and a maximum dimension G_{py} in the y dimension, though the subgratings can be different shapes and sizes in other embodiments.

[0025] Subgratings $g_{i,j}$ are arranged in a two-dimensional array with a number g_x along the X axis and a number g_y along the Y axis. Both subgrating numbers g_x and g_y are six in this simple example, but either or both numbers can be the same or different. The array of pixels $p_{i,j}$ includes a number p_x along the X axis and a number p_y along the Y axis. Numbers p_x and p_y are nine and eleven, respectively, but either or both can be different.

[0026] Pixel count p_x is coprime with the subgrating count g_x along the X axis and between edges 109L and 109R; that is, pixel numbers p_x and g_x between portions 111L and 111R share no common integer factor other than one. Likewise, the pixel count p_y is coprime

with the subgrating count g_y along the Y axis and between edges 109F and 109B. With this arrangement, imaging device 100 obtains p_x times p_y independent samples of the interference pattern created by a single instance of a subgrating $g_{i,j}$. The effective pixel pitch is $1/g_y$ times pixel pitch P_y in the Y dimension and $1/p_x$ times the pixel pitch P_x in the X dimension. Unless otherwise specified, the X and Y dimensions refer to the Cartesian coordinate system defined by the array of subgratings.

[0027] Though not shown, pixel arrays can include superfluous pixel structures that are e.g. defective or redundant and/or for various other reasons may not be used for image capture. Such superfluous structures may not be “pixels” as that term is used herein, as that term generally refers to elements that provide a measurement of illumination that is used for image acquisition. Redundant pixels can be used to take multiple measurements of pixels in equivalent positions, reducing noise.

[0028] Figure 3 shows IR imaging device 100 of Figures 1 and 2 with the full tessellation of subgratings $g_{i,j}$ that make up phase grating layer 105. The boundaries between subgratings $g_{i,j}$ are contiguous across tessellation borders, so the borders are not easily visible. Individual subgratings are nevertheless readily identifiable with reference to their Cartesian coordinates expressed along the X axis as $g_x[5:0]$ and along the Y axis as $g_y[5:0]$. For example, subgrating $g_{5,5}$ in the upper right corner is located in the intersection of column g_x5 and row g_y5 . Pixels $p_{i,j}$ are likewise identifiable along the X axis as $p_x[8:0]$ and along the Y axis as $p_y[10:0]$.

[0029] Figure 4 is a cut-away view of imaging device 100 of Figures 1-3. Grating layer 105 is a binary, odd-symmetry silicon phase grating of thickness t separated from pixel array 107 array of pixels $p_{i,j}$ by an air interface of optical height h equal to $300\mu\text{m}$. (In general, optical height h is the sum, for every material between grating 105 and pixel array 107, of the physical height divided by the index of refraction through that material. Silicon is a relatively inexpensive material that has high IR transmission, and it can be patterned using well-known semiconductor processes. Other materials are suitable, however, and can be selected for different wavelengths, or for other material or cost considerations. Thickness t and height h are $500\mu\text{m}$ and $300\mu\text{m}$, respectively. Pixel pitch P_x along the X dimension is about $100\mu\text{m}$; pixel pitch P_y (Figure 2) is similar. Any or all of these dimensions can vary in other embodiments.

[0030] Height h can be related to the wavelength of incident light, width W of widest portions of phase features 110 and 115, and the grating design. The phase features contain

some extended elements longer than they are wide. Let the typical widths of these elements be W and a wavelength within the band of interest be λ . Height h , the effective optical vertical separation between phase-generating layer 105 and pixel array 107, follows the formula $h = W^2/(k*\lambda)$ where "k" is a constant governed by the grating design. For phase antisymmetric gratings using two free parameters (or "interference fringes"), the optimal value for k may be in the range of two to six; more generally k may range from approximately 0.3 to 10. Broadly speaking, the optimal k tends to be towards the low end of this range in designs using more interference fringes, and towards the higher end of this range with smaller numbers of interference fringes. In one embodiment, width W of one of the thickest arms is about 120 microns, the effective optical height h is 416 microns, and the wavelength λ is about 10 microns. Substituting into the formula $k = W^2/\lambda/h$, the value k for this embodiment is about 3.4. Grating 105 has a value k in the range of from about two to six, though k can be outside this range (e.g., between 1.5 and 5) in other embodiments.

[0031] Adjacent features 110 and 115 form six illustrative odd-symmetry boundaries 400, each indicated using a vertical, dashed line. The lower features 115 induce phase retardations of half a wavelength (π radians) relative to upper features 110. Features 405 and 410 on either side of each boundary exhibit odd symmetry. With this arrangement, paired features induce respective phase delays that differ by approximately half a wavelength λ over the wavelength band of interest, approximately $5\mu\text{m}$ (half of $10\mu\text{m}$) in this example for imaging within the IR spectrum. The different phase delays produce curtains of destructive interference separated by relatively bright foci to produce an interference pattern on pixel array 107. Stepped features 405 and 410 are of uniform width in this simple illustration, but vary across each subgrating $g_{i,j}$ and collection of subgratings. Curved and divergent boundaries of odd symmetry, as illustrated in Figures 1-3, provide rich patterns of spatial modulations that can be processed to extract photos and other image information from a scene.

[0032] Pixel array 107, also called a "thermographic" or "thermal-imaging" array, can be cooled to support certain types of IR sensitive semiconductors. Cooling adds complexity and cost, and requires power. The pixels in uncooled detectors are mostly based on pyroelectric and ferroelectric materials or microbolometer technology. Uncooled sensors may provide inferior image quality, but can be substantially simpler, smaller, and less expensive.

[0033] Imaging device 100 includes an integrated circuit (IC) device 415 that supports image acquisition and processing. IC 415 includes a processor 420, random-access memory

(RAM) 425, and read-only memory (ROM) 430. ROM 430 can store a digital representation of the point-spread function (PSF) of grating layer 105 from which a noise-dependent deconvolution kernel may be computed. ROM 430 can also store the deconvolution along with other parameters or lookup tables in support of image processing. Processor 420 captures digital image data from the pixel array and uses that data with the stored PSF to compute e.g. images and other image data. Processor 420 uses RAM 425 to read and write data in support of image processing. Processor 420 may support specialized processing elements that aid fast, power-efficient Fourier- or spatial-domain deconvolution, for example. All the components of device 100 can be integrated into the same device or package using microfabrication techniques.

[0034] Figure 5 depicts imaging device 100 with the details of subgratings $g_{i,j}$ obscured for ease of illustration. The boundaries of subgratings $g_{i,j}$ are highlighted using lines that are bold relative to those of the underlying array of pixels $p_{i,j}$. A single pixel $p_{7,6}$ is also highlighted using a bold border. A dot in the center of pixel $p_{7,6}$ serves as a reference for pixel position relative to the subgrating array, and need not correspond to any physical structure. A point elsewhere on each pixel—e.g. a corner—could serve as a similar reference.

[0035] The center of pixel $p_{7,6}$, with reference to the array of subgratings, is located at $gx3+\text{mod}(px7,gx)$ in the X dimension and $gy2+\text{mod}(py6,gy)$ in the Y dimension. The displacements $\text{mod}(px7,gx)$ and $\text{mod}(py6,gy)$ place the center of pixel $p_{7,6}$ within overlaying subgrating $g_{4,3}$. The combination of $\text{mod}(px7,gx)$ and $\text{mod}(py6,gy)$ for pixel $p_{7,6}$ is unique among pixels $p_{i,j}$ with reference to their corresponding subgratings. The same is true of the remaining pixels. That is, no two pixels $p_{i,j}$ are located at the same position relative to their respective subgrating. Moreover, the modulo coordinates are evenly spaced along the X and Y axes.

[0036] Figure 6 depicts imaging device 100, again with the details of subgratings $g_{i,j}$ obscured for ease of illustration, with certain pixels shaded to illustrate their respective contributions. Each physical pixel $p_{i,j}$ maps to a virtual location, similarly shaded, beneath a virtual archetypical subgrating Vg (at left). In the Y dimension, each of the four highlighted pixels is located a respective modulo gy from the lower boundary of its corresponding subgrating. These modulo are separated from one another by an offset Py/gy , which provides a virtual pixel size of the same extent. Though not shown, similar offsets for pixels along the X dimension provide a virtual pixel size of Px/gx . Pixels $p_{i,j}$ are thus distributed evenly in both the X and Y dimensions relative to the row and column intersections of the subgrating grid. The combination of the arrays of subgratings $g_{i,j}$ and pixels $p_{i,j}$ can thus be modeled as a

single virtual subgrating V_g (top) with the same number of virtual pixels as there are pixels $p_{i,j}$. Imaging device 100 thus provides p_x times p_y independent measurements of the interference pattern from an archetypical subgrating.

[0037] The number of unique modulo coordinates preserves the resolution provided by pixel array 107. The even spacings of the modulo coordinates in the X and Y dimensions simplifies the mathematics required to extract image information using e.g. Fourier deconvolution, and thus limits the time and processing power required for image processing.

[0038] Due to the finite size of each pixel, there will be some spatial frequencies whose period in either of the X or Y dimensions fits an integral number of times into the pixel extent in that dimension, and thus may not be observed by device 100. Such frequencies can be in the null space for imaging tasks. However, the precise spatial frequencies causing such nulls may not be part of the discrete Fourier basis of frequencies describing a finite-sized sensor array. In other words, while the frequency response of the pixels incurs a sinc penalty from the square-wave profile of the pixels, this sinc (which has zeros) will not in general be sampled at its zeros if the total lateral dimensions of the array are not integer multiples of the extent of the pixel. In imaging device 100, for example, there is no spatial frequency in the discrete-Fourier-transform basis that cannot be sampled, so the system has full rank, and, with a sufficiently high signal-to-noise ratio (SNR), can produce images with as many free parameters as there are pixels.

[0039] Figure 7A depicts an imaging device 700 in accordance with another embodiment. A nine-by-nine array of pixels $p_{i,j}$ underlies a three-by-three array of subgratings $g_{i,j}$. The patterns of all but one subgrating $g_{2,0}$ are omitted so as not to obscure the underlying pixel locations. Nine pixels are shaded to illustrate their positions relative the overlying subgratings. The columns of subgratings $g_{i,j}$ are offset from the columns of pixels $p_{i,j}$ by an angle θ , the arctangent of which is one half in this example. This angle and the size of the subgratings are selected to map the physical pixels to unique virtual locations with respect to an archetypal subgrating. In this example, each of the shaded pixels maps to a unique virtual location with respect to its overlying subgrating.

[0040] Figure 7B depicts imaging device 700 rotated by angle θ . Each subgrating $g_{i,j}$ is divided into nine equal regions using dashed lines. The nine subgratings $g_{i,j}$ collectively cover all eighty-one pixels, and the center of each shaded pixel underlies a unique region within a corresponding subgrating. For example, taking the lower left corner of device 700 as g_{x0}/g_{y0} , the center of pixel $p_{7,7}$ is located at $g_{x2} + \text{mod}(p_{x7}, g_x)$ in the X dimension and

$gy1+\text{mod}(py7,gy)$ in the Y dimension. As in prior examples, the X and Y dimensions refer to the Cartesian coordinate system defined by the array of subgratings. The values $px7$ and $py7$ can be expressed as trigonometric functions of pixel pitches px and py and angle θ .

[0041] The displacements $\text{mod}(px7,gx)$ and $\text{mod}(py7,gy)$ place the center of pixel $p_{7,7}$ within overlaying subgrating $g_{2,1}$. The combination of $\text{mod}(px7,gx)$ and $\text{mod}(py7,gy)$ for pixel $p_{7,7}$ is unique among pixels $p_{i,j}$ with reference to their corresponding subgratings, and the same is true of the remaining pixels. The centers of the shaded pixels are evenly spaced along the X and Y axes. The combination of the array of subgratings $g_{i,j}$ and the shaded pixels $p_{i,j}$ can thus be modeled as a single virtual subgrating 750 with three rows and three columns of evenly spaced virtual pixels.

[0042] Figure 8A depicts imaging device 700 of Figures 7A and 7B with the array of pixels $p_{i,j}$ oriented at angle θ relative to the array of subgratings $g_{i,j}$ as in the example of Figure 7B. Pixels $p_{i,j}$ are square and have a pitch Pp ; subgratings $g_{i,j}$ are also square, and have a pitch $Pg = \frac{9}{\sqrt{5}}(Pp)$; and the angle $\theta = \tan^{-1} \frac{1}{2}$. The center of each pixel is marked with a small circle, each shaded or filled to identify them as members of groups of pixels associated with corresponding subgratings. For example, pixel $p_{0,0}$ is shaded like the other pixels beneath subgrating $g_{0,1}$.

[0043] Figure 8B depicts the nine subgratings $g_{i,j}$ of imaging device 700 of Figure 8A separated and the pixel outlines omitted to highlight the constellations of pixel centers for each subgrating. Because the location of each pixel center relative to its overlying subgrating is unique among the pixels, device 700 provides the same number of interdependent measurements as there are pixels in the array.

[0044] Figure 8C depicts an archetypal subgrating 860 encompassing all the constellations of pixel centers from the nine subgratings $g_{i,j}$ of e.g. Figures 8A and 8B. The constellations combine such that the center of each pixel $p_{i,j}$ occupies one of eighty-one unique locations arranged in nine rows and nine columns relative to the archetypal subgrating. The row and columns are evenly spaced by an effective pixel pitch P_{ef} that is one-ninth grid pitch Pg , or pixel pitch Pp divided by the square root of five. The even spacings of the modulo coordinates of pixels $p_{i,j}$ relative to the subgrating array facilitates Fourier deconvolution for image recovery and analysis.

[0045] Figure 9 depicts an imaging device 900 in accordance with another embodiment. A seven-by-six array of pixels 905 of pitch Px in the X dimension and pitch Py in the Y dimension is disposed beneath an array of subgratings 910. Subgratings 910 are of the same

size and aspect ratio as pixels 905, but the array of subgratings is offset by an angle Φ , the tangent of which is $\frac{3}{4}$ in this example. This relative orientation is represented using as a 3-4-5 triangle 912, a Pythagorean triple. This arrangement produces five classes of subgrating/pixel alignment, with each class representing a specific relative alignment and placement of a pixel vis-a-vis the overlying subgrating. Pixels 905 that are members of the same class are highlighted using the same manner of shading. The topographical features of subgratings 910 are omitted here to show the relative placement and orientation of pixels 905.

[0046] The five leftmost pixels 905 in the lowermost row include a member from each class. The leftmost corner of each of these pixels is marked with a circle to provide a reference point relative to the respective overlaying subgrating 910. Each of these reference points is mapped to an archetypal subgrating 915, with the resulting constellation of circles 920 representing the positional diversity of each class of pixel relative to its respective and identical subgratings. The five circles 920 are distributed evenly in both the X and Y dimensions relative to the row and column intersections of the subgrating gird. The incremental spacing in the X dimension is $P_x/5$, where P_x is the pixel and subgrating pitch in the X dimension; the incremental spacing in the Y dimension is $P_y/5$, where P_y is the pixel and subgrating pitch in the Y dimension. In this particular arrangement, each pixel 905 in the array remaps to one of these five locations. The array of subgratings $g_{i,j}$ and pixels $p_{i,j}$ can thus be modeled as a single virtual subgrating 915 with five virtual pixels evenly spaced in the X and Y dimensions. Imaging device 900 thus provides five-times oversampling and increased resolution relative to the pixel array.

[0047] Figure 10 depicts an imaging device 1000 similar to the device 900 of Figure 9 but reoriented such that the rows and columns of pixels 905 are horizontal and vertical in the view, as would be expected—though not necessary—for a camera of this type. Subgrating $g_{i,j}$ are tiled with copies extending beyond the borders of the pixel array 1010 by portions 1005 of sufficient extent to cover all angles from which incident light is likely to strike array 1010. Portions 1005 extend the interference pattern in support of Fourier-domain image processing.

[0048] Figure 11 depicts an imaging device 1100 in accordance with another embodiment. A 25x25 array of pixels 1105 is disposed beneath an array of identically sized subgratings 1110 offset by an angle Φ_2 , the tangent of which is $\frac{7}{24}$. This relative orientation is represented using as a 7-24-25 triangle 1112, another Pythagorean triple. This arrangement produces twenty-five classes of subgrating/pixel alignment. Pixels 1105 that are members of one of those classes are highlighted by shading. The location of each pixel 1105 maps to one of twenty-five locations within an archetypal subgrating. As in prior examples, these

locations are spaced evenly in the X and Y dimensions of the subgrating array. The incremental spacing in the X dimension is $P_x/25$ and in the Y dimension $P_y/25$, where P_x and P_y are the pitches of the pixel array. The array of subgratings 1110 and pixels 1105 can be modeled as a single virtual subgrating with twenty-five virtual pixels evenly spaced in the X and Y dimensions. Imaging device 1100 thus provides twenty-five-times oversampling.

[0049] Figure 12 depicts imaging device 1100 of Figure 11 with subgratings 1110 trimmed around the perimeter. The subgratings extend beyond the boundaries of the pixel array so that the foci and curtains produced by subgratings 1110 are continuous over the angles of incident light.

[0050] Figure 13 depicts an imaging device 1300 in accordance with another embodiment. Viewed from a perspective normal to the active surface, device 1300 includes a phase grating layer 1305 above a pixel array 1310. Grating layer 1305 includes a pattern of grating features that produce interference patterns as detailed previously, and is formed of a material suitable for the wavelength band of interest (e.g., for visible light).

[0051] Phase grating layer 1305 includes left and right portions 1315L and 1315R that extend beyond the respective left and right edges of the underlying pixel array 1310. Portion 1315R extends to the right of pixel array 1310, repeating the pattern that extends to the right of the left boundary 1320L of pixel array 1310; portion 1315L extends to the left of pixel array 1310, repeating the pattern that extends to the left of the right boundary 1320R; portion 1315B extends beyond edge 1320B of pixel array 1310, repeating the pattern that extends over the pixel array from front boundary 1320F; and portion 1315F extends beyond edge 1320F of pixel array 1310, repeating the pattern that extends over the pixel array from back boundary 1320B. These extensions of the grating pattern extend the interference pattern in support of Fourier-domain strategies.

[0052] The pixels of array 1310 are relatively large in this example. The pitches in each dimension are no bigger than about one-third the widest dimension of one of the spiral arms formed by the grating features, and can be much smaller. In one embodiment, for example, pixel array 1310 is 160x160 pixels.

[0053] Figure 14 depicts an imaging device 1400 in accordance with another embodiment. Device 1400 includes a phase grating layer 1405 above a pixel array (not shown). Grating layer 1405 includes a pattern of grating features that produce interference patterns as detailed previously. Layer 1405 includes left and right portions 1415L and 1415R that extend beyond the respective left and right edges 1420L and 1420R of the underlying pixel array. Portion 1415R extends to the right of the pixel array, repeating the pattern that

extends to the right of the left pixel boundary 1420L; portion 1415L extends to the left of the pixel array, repeating the pattern that extends to the left of the right pixel boundary 1420R; portion 1415B extends beyond edge 1420B, repeating the pattern that extends over the pixel array from front pixel boundary 1420F; and portion 1415F extends beyond edge 1420F, repeating the pattern that extends over the pixel array from back pixel boundary 1420B. These extensions of the grating pattern extend the interference pattern in support of Fourier-domain strategies.

[0054] The grating features form asymmetrically shaped four-point “stars” with curved boundaries. Such shapes can be described mathematically by starting with identical, evenly spaced elements that approximate the desired shapes. The x/y locations of the points making up these elements are then translated by an amount that depends on x and y, where this translation is smooth.

[0055] One approach to creating a pattern of the type illustrated for grating layer 1405 is as follows. First, a pattern composed of identical, evenly spaced elements is laid out to span the dimensions of the area to be patterned. The pattern can be composed of polygons that collectively describe the grating shape. Next, every point (x,y) in the pattern is translated by an amount that depends on x and y, where this translation is smooth, and also has X, Y periodicity in x and y, where X and Y are the width and height of the underlying pixel array. This translation can be accomplished by replacing every location (x,y) in the pattern with (x+F(x,y), y+G(x,y)), where F and G have the following properties.

1. Periodicity: $F(x+X,y) = F(x,y) = F(x,y+Y)$; and $G(x+X,y) = G(x,y) = G(x,y+Y)$.
2. Smoothness, with at least some minimal amplitude: the derivatives of F and G with respect to x and y are not too big (which would distort the local grating shapes too much) nor too small (which would make the gratings essentially the same as their neighbors).
3. No internal repetitions: if $F(x+D,y) = F(x,y)$ for all x and y, then D must be an integral multiple of X; similar constraints apply to F's y repetition, and G's x and y repetitions.

Property 3 avoids introducing equivalent phase gratings within an X-Y tile. As detailed above, with a coprime or tilted sampling strategy this condition is not always necessary to guarantee that each measurement gives new information. Furthermore, in some embodiments known internal repetitions introduce deliberate redundancy, used to enhance signal to noise ratio or provide robustness against dead pixels.

[0056] One way to satisfy the above is to make F and G of the following form: $A \cos(2 \pi$

$\pi * x/X + \phi_1) + B \cos(2 * \pi * y/Y + \phi_2)$. A and B are amplitudes, X is the width and Y the height of the active pixels, and ϕ_1 and ϕ_2 are phase factors. The parameters A, B, ϕ_1 and ϕ_2 may be different for F and G, but X and Y are the same for F and G.

[0057] While the subject matter has been described in connection with specific embodiments, other embodiments are also envisioned. For example, the wavelength band of interest can be broader or narrower than those of the foregoing examples, and may be discontinuous. A linear array of pixels can be used alone or in combination with other linear arrays to sense one-dimensional aspects of a scene from one or more orientations. Moreover, if a given subgrating exhibits some Fourier nulls, then two or more general regions that potentially have different aspect ratios, grating designs or orientations, or any combination of the above, could provide independent measurements of the scene. Other variations will be evident to those of skill in the art. Therefore, the spirit and scope of the appended claims should not be limited to the foregoing description. Only those claims specifically reciting “means for” or “step for” should be construed in the manner required under the sixth paragraph of 35 U.S.C. §112.

CLAIMS

What is claimed is:

1. An imaging device comprising:
a pixel array having a first edge and a second edge opposite the first edge; and
a phase grating layer over the pixel array and including a pattern of subgratings,
wherein:
a first portion of the phase grating layer extends beyond the second edge away from the pixel array, the first portion beginning a repeat of the pattern from the first edge to the second edge; and
a second portion of the phase grating layer extends beyond the first edge away from the pixel array, such second portion beginning a repeat of the pattern from the second edge to the first edge.
2. The imaging device of claim 1, further comprising:
a first subgrating number g_x of the subgratings along a first axis X between the first edge and the second edge; and
a first pixel number p_x , coprime with the first subgrating number g_x , of the pixels along the first axis X and between the first edge and the second edge.
3. The imaging device of claim 2, the pixel array having a third edge and a fourth edge opposite the third edge, wherein
a third portion of the phase grating layer extends beyond the fourth edge away from the pixel array, the third portion beginning a repeat of the pattern from the third edge to the fourth edge; and
a fourth portion of the phase grating layer extends beyond the third edge away from the pixel array, such fourth portion beginning a repeat of the pattern from the fourth edge to the third edge.
4. The imaging device of claim 3, further comprising:
a second subgrating number g_y of the subgratings along a second axis Y between the third edge and the fourth edge; and
a second pixel number p_y , coprime with the second subgrating number g_y , of the pixels along the second axis Y and between the third edge and the fourth edge.
5. The imaging device of claim 1, wherein each subgrating includes a minimum

dimension, and wherein the first portion extends beyond the second edge by at least the minimum dimension.

6. The imaging device of claim 5, wherein second portion extends beyond the first edge by at least the minimum dimension.

7. The imaging device of claim 1, wherein the pixel array includes rows of pixels and the pattern of the subgratings comprises rows of subgratings that extend at an angle relative to the rows of pixels.

8. The imaging device of claim 7, wherein the angle is of a Pythagorean triple.

9. The imaging device of claim 1, wherein the subgratings are identical.

10. The imaging device of claim 1, the phase grating to cast an interference pattern on the pixel array, each subgrating including boundaries of odd symmetry separating stepped features on opposite sides of each boundary, the stepped features on the opposite sides of each boundary offset from the pixel array by half of a wavelength within a wavelength band of interest, plus an integer multiple of the wavelength, to produce curtains of destructive interference at the pixel array.

11. The imaging device of claim 1, further comprising superfluous pixels.

12. The imaging device of claim 11, wherein the superfluous pixels comprise defective pixels.

13. The imaging device of claim 1, wherein the phase grating comprises silicon.

14. The imaging device of claim 13, wherein the phase grating consists essentially of silicon.

15. An imaging device comprising:
an array of pixels;
a phase grating over the array of pixels and including an array of subgratings;
wherein each pixel includes a pixel center beneath a corresponding one of the subgratings at a pixel location that is modulo a coordinate in the array of subgratings of the corresponding one of the subgratings; and
wherein the modulus are evenly spaced with respect to the array of subgratings.

16. The imaging device of claim 15, the array of pixels including p_x columns and p_y rows of the pixels.
17. The imaging device of claim 16, the array of subgratings including g_x columns and g_y rows of the subgratings, wherein each pixel location has a different modulo along at least one of the columns of subgratings and the rows of subgratings.
18. The imaging device of claim 15, wherein the phase grating consists essentially of silicon.
19. The imaging device of claim 15, wherein the subgratings are identical.
20. The imaging device of claim 15, further comprising superfluous pixels.
21. The imaging device of claim 15, further comprising additional subgratings above locations outside the array of pixels.
22. The imaging device of claim 21, where the additional subgratings seamlessly abut the array of subgratings.

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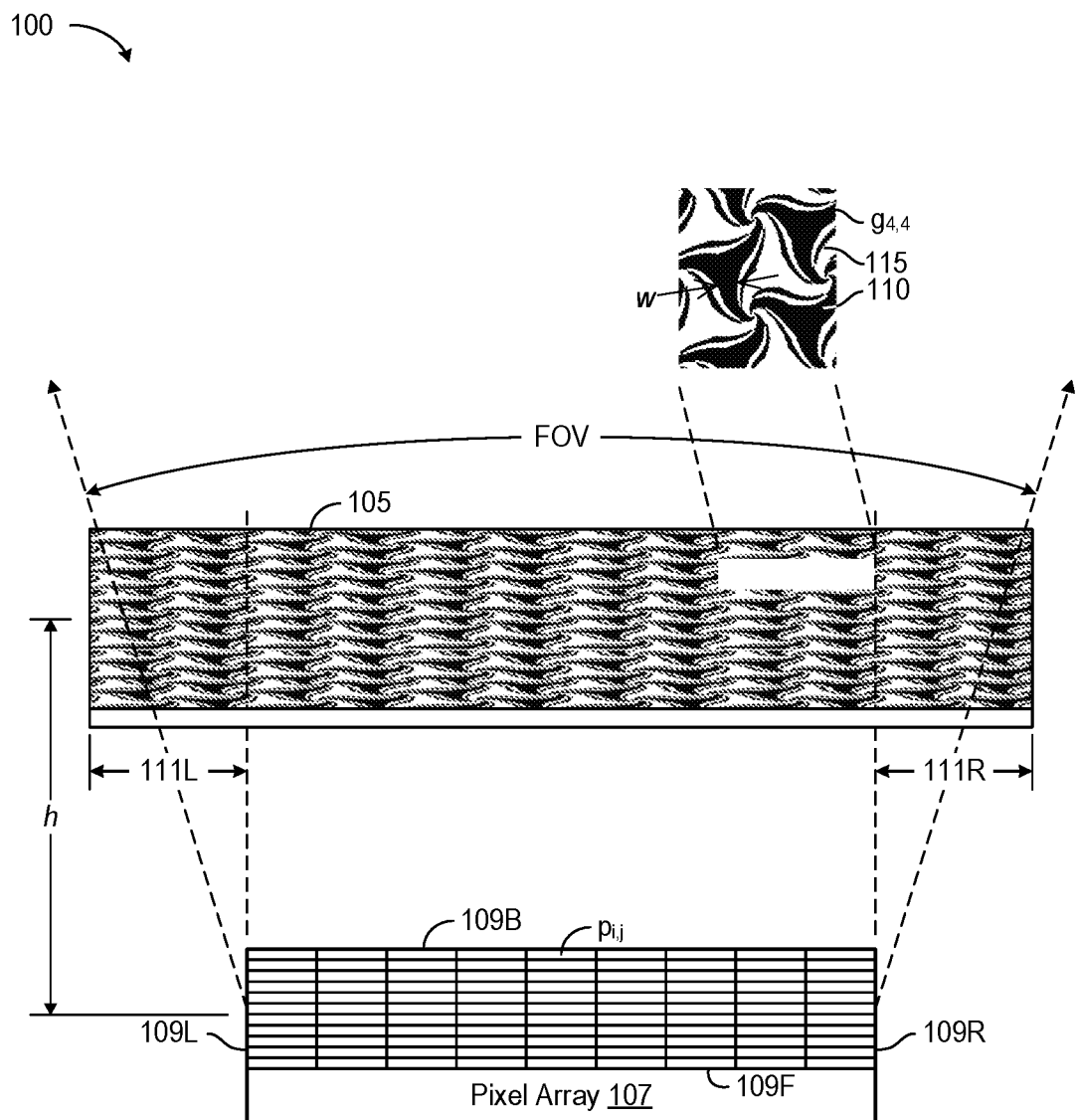


FIG. 1

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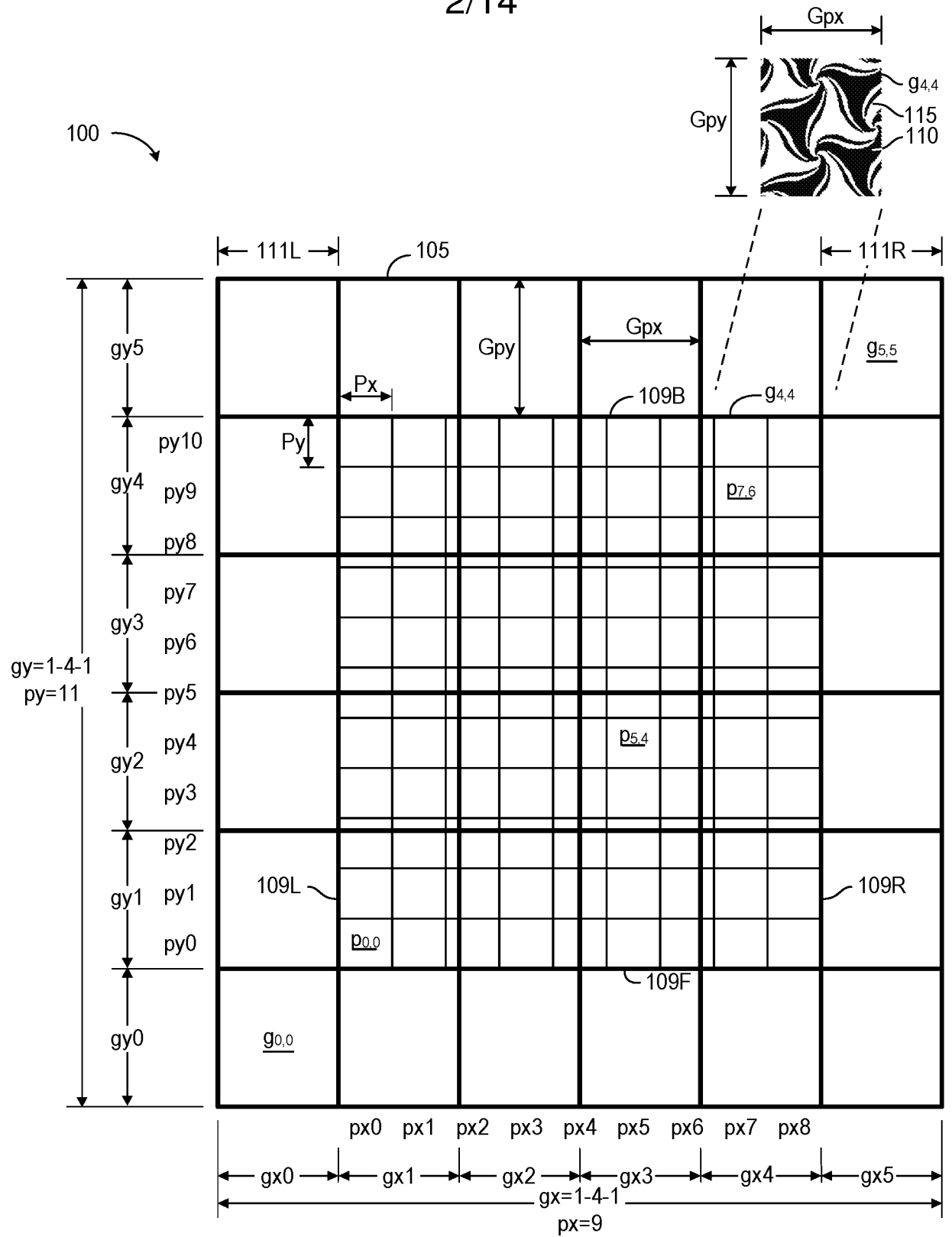


FIG. 2

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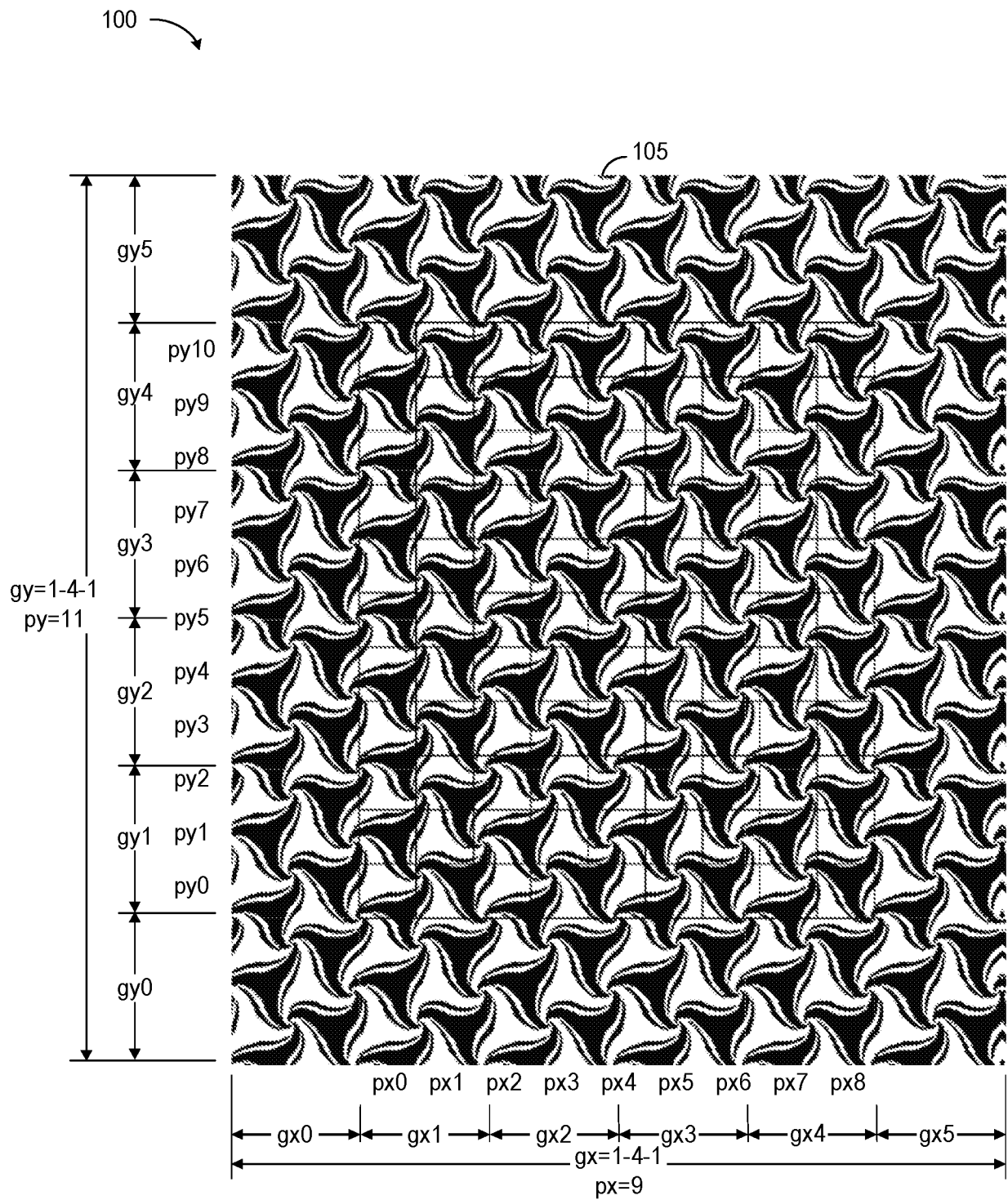


FIG. 3

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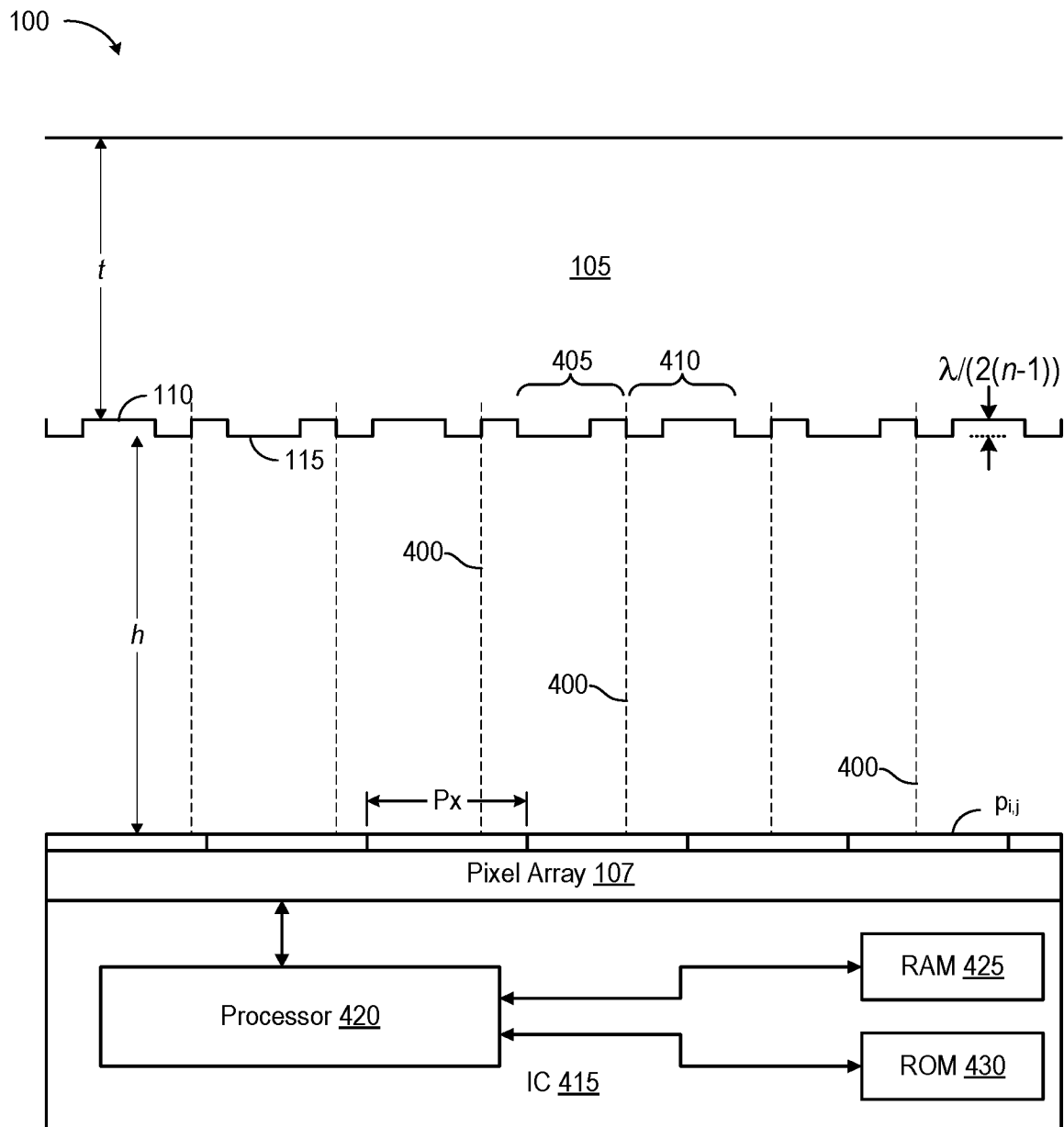


FIG. 4

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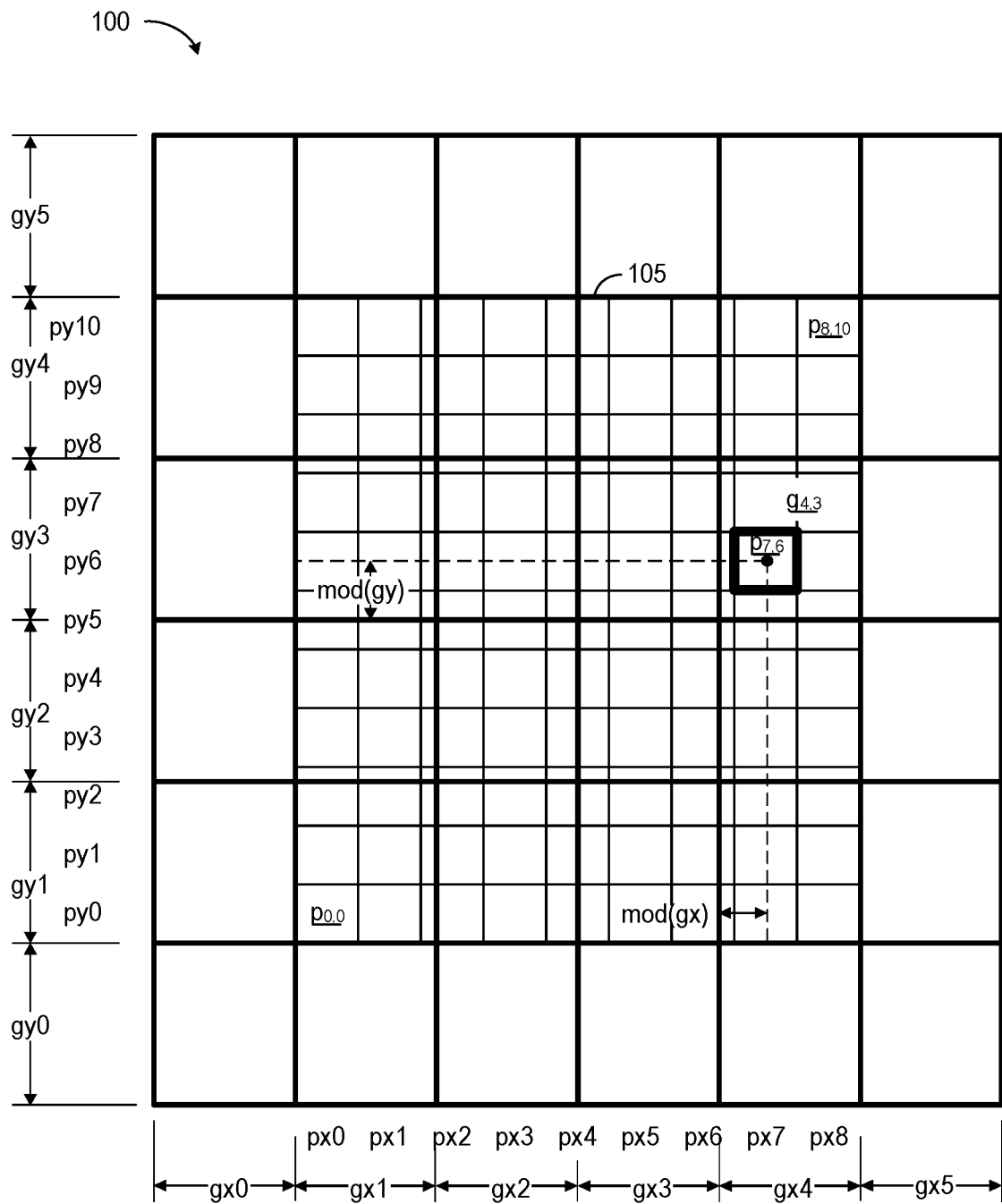


FIG. 5

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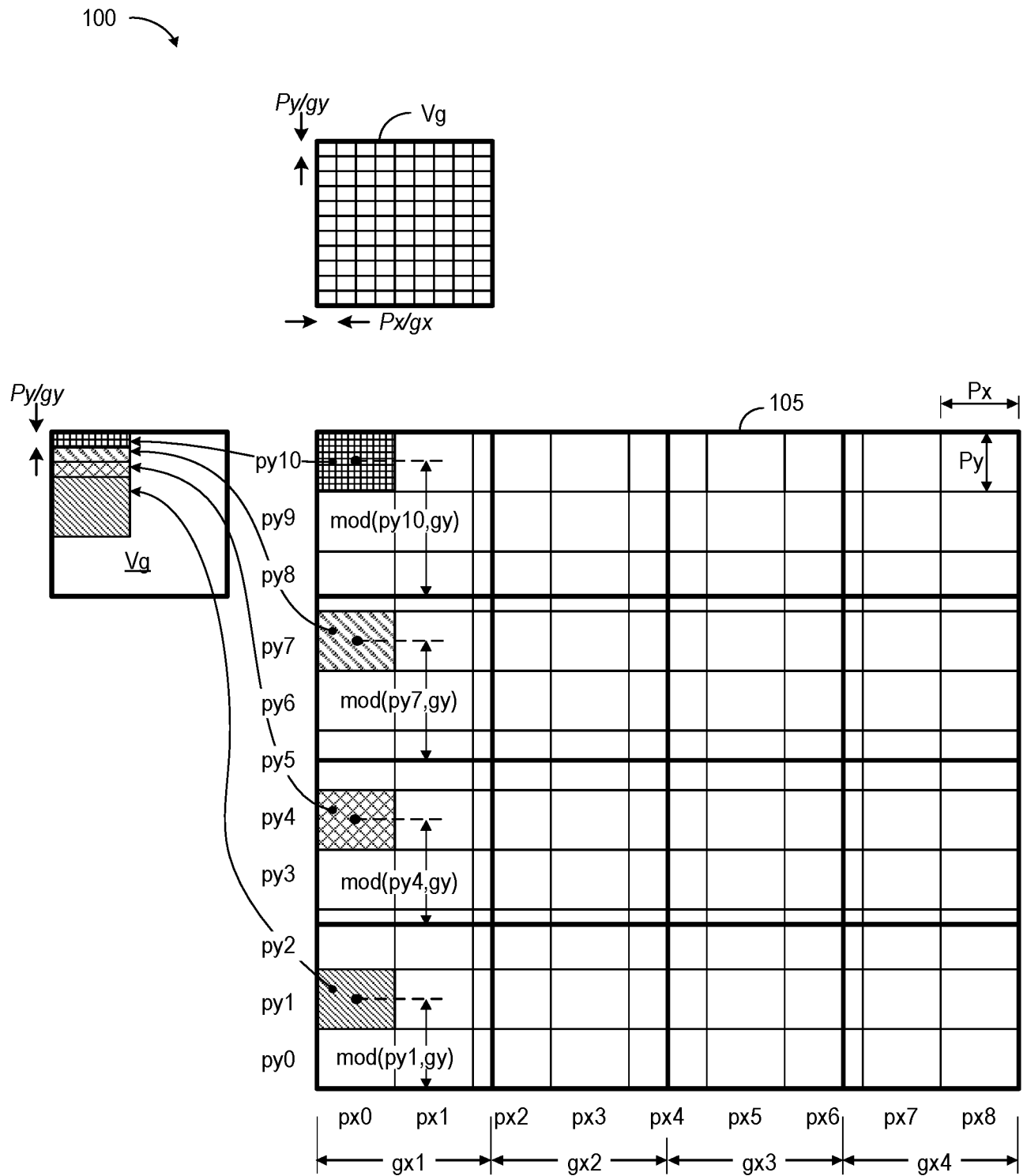


FIG. 6

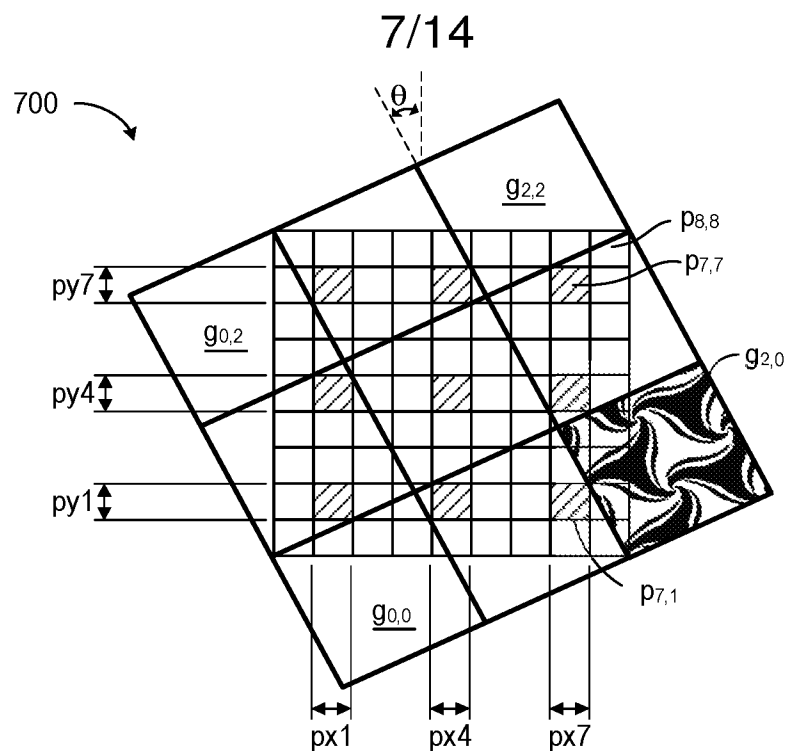


FIG. 7A

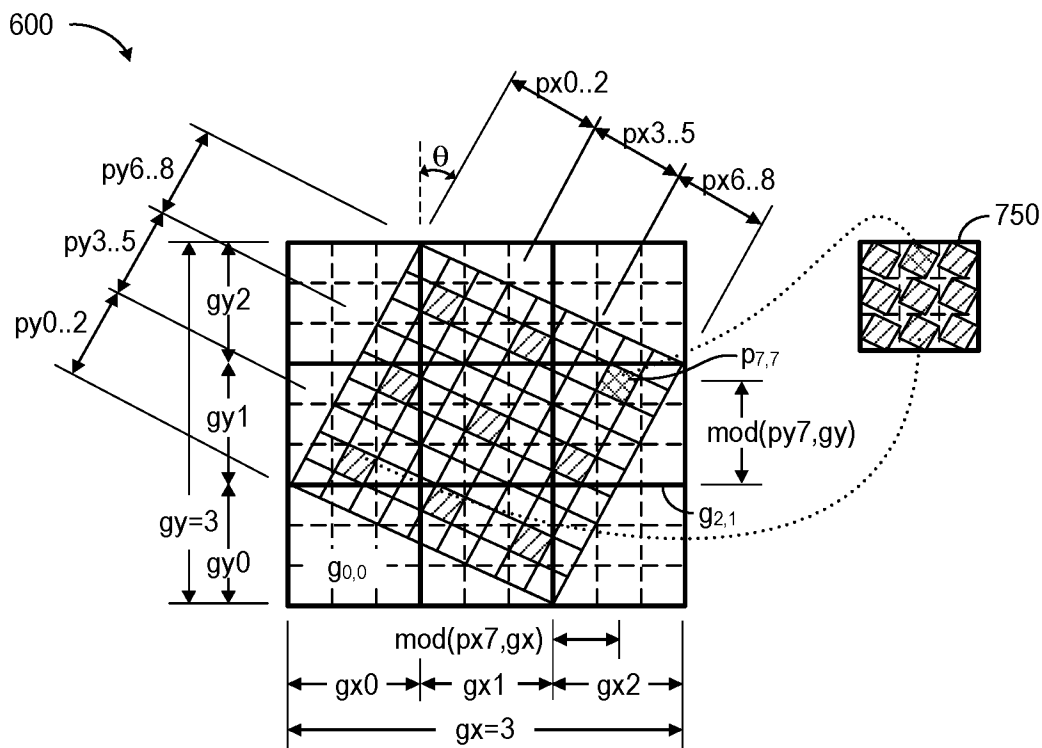
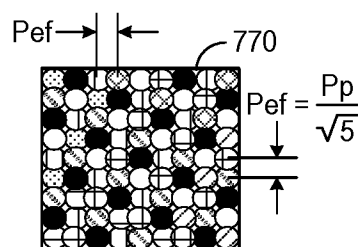
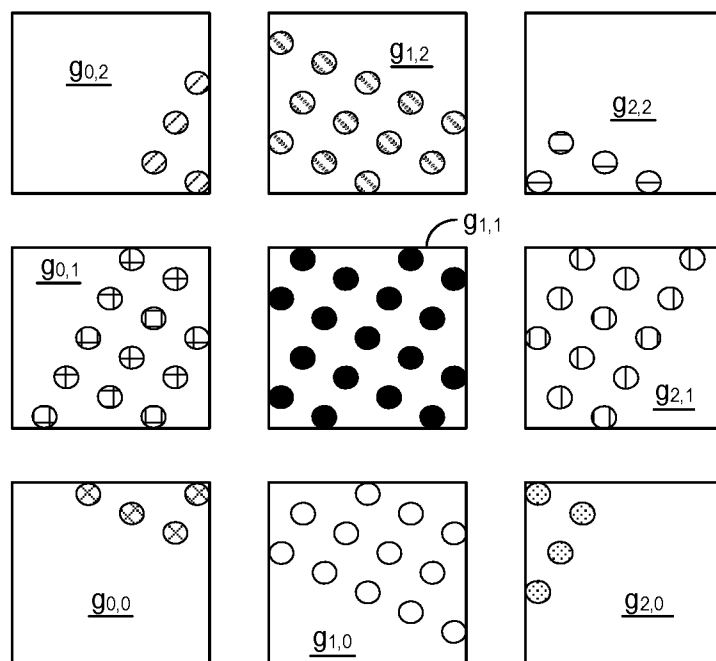
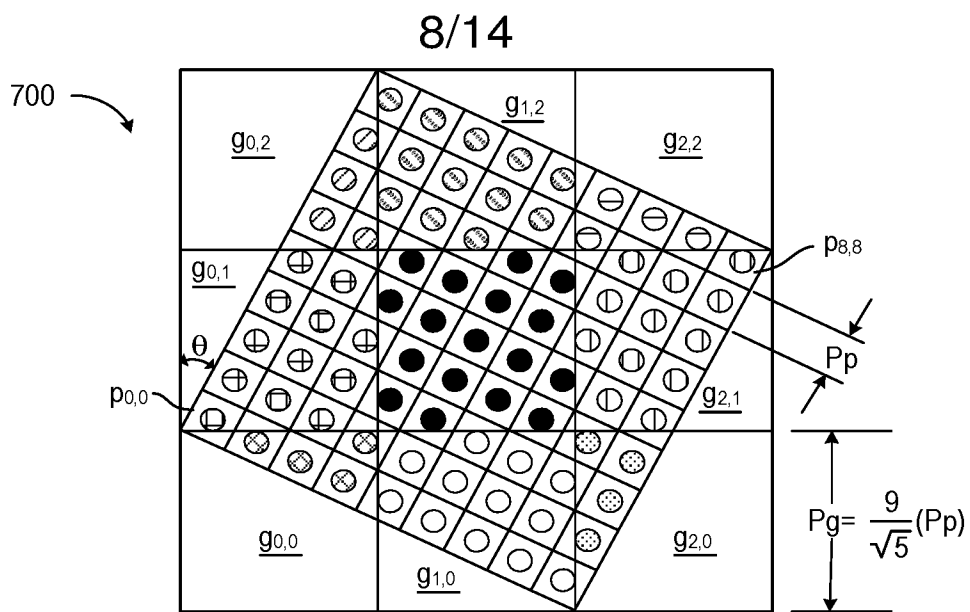


FIG. 7B



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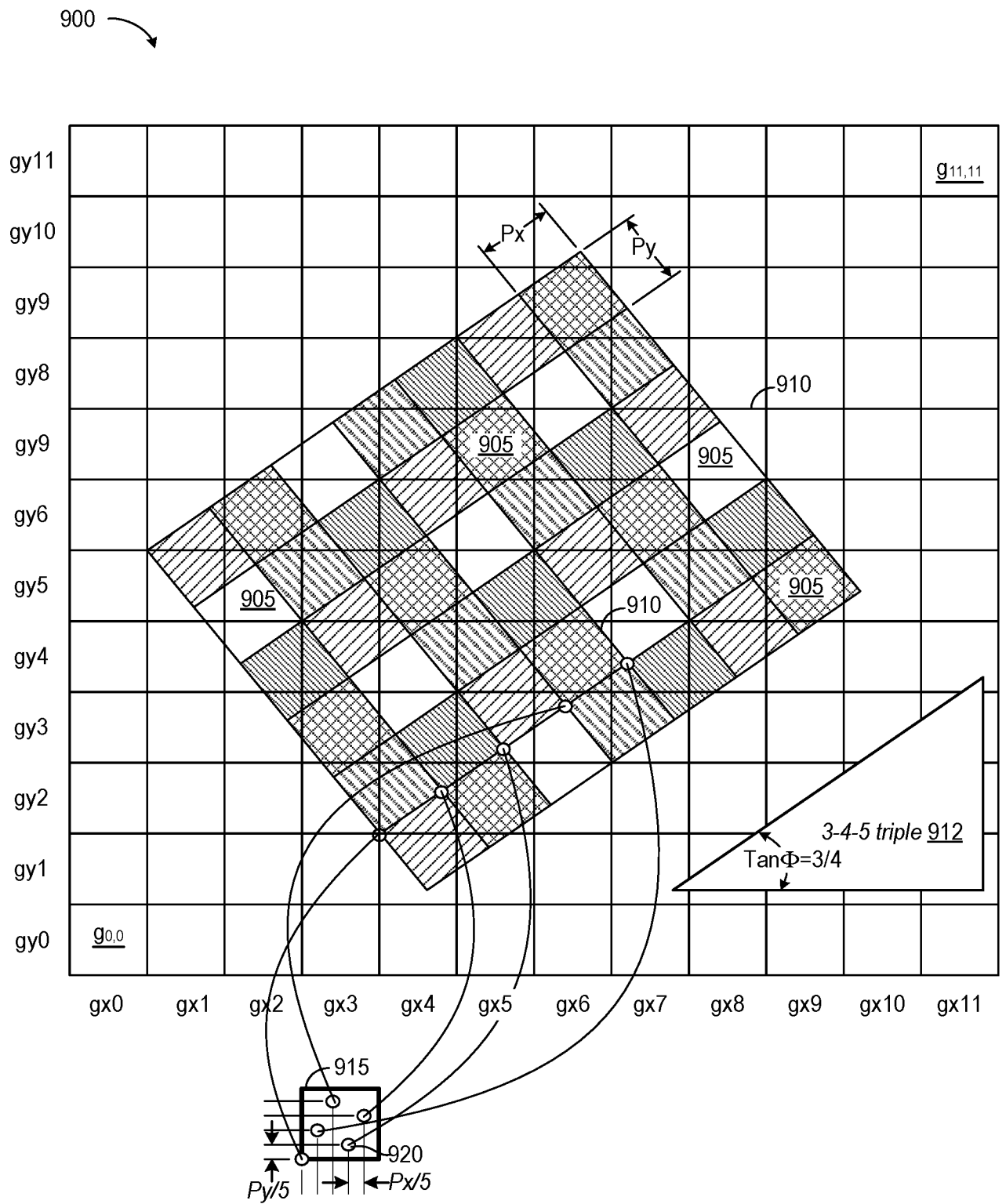


FIG. 9

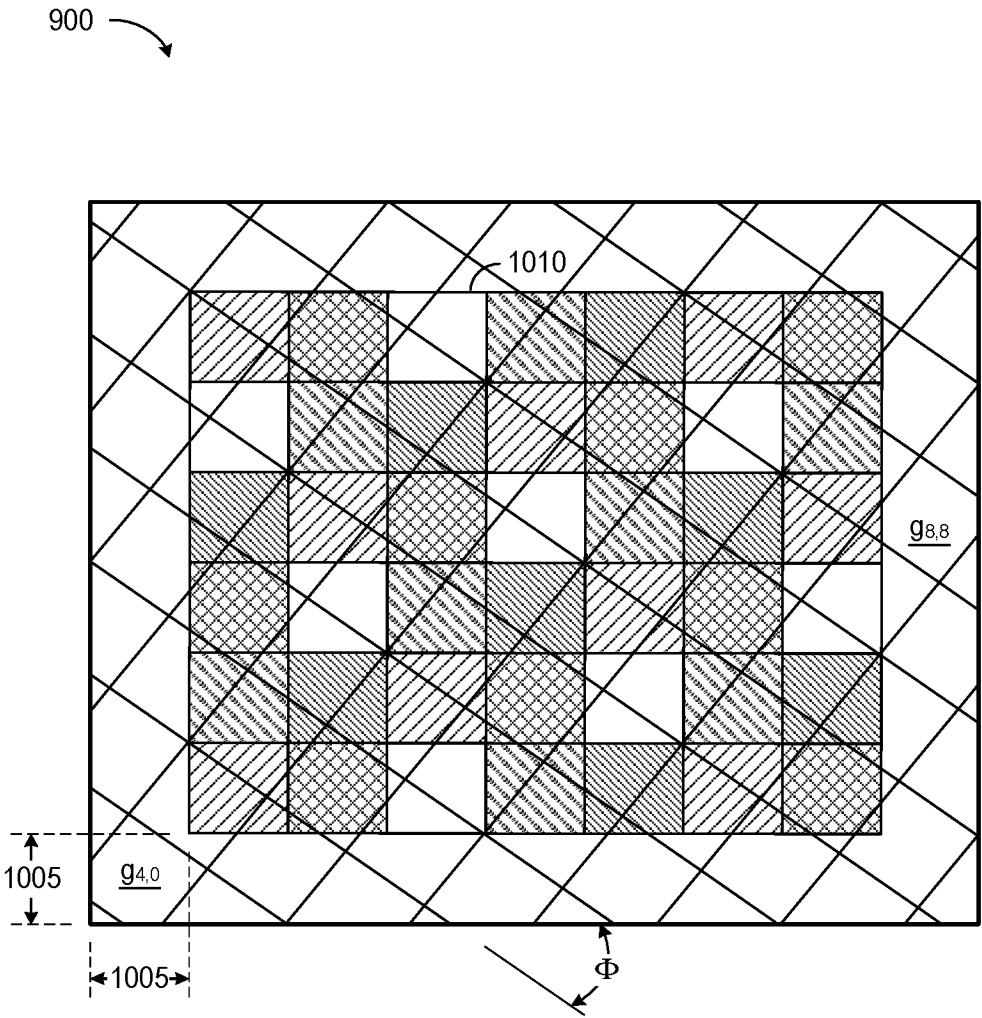


FIG. 10

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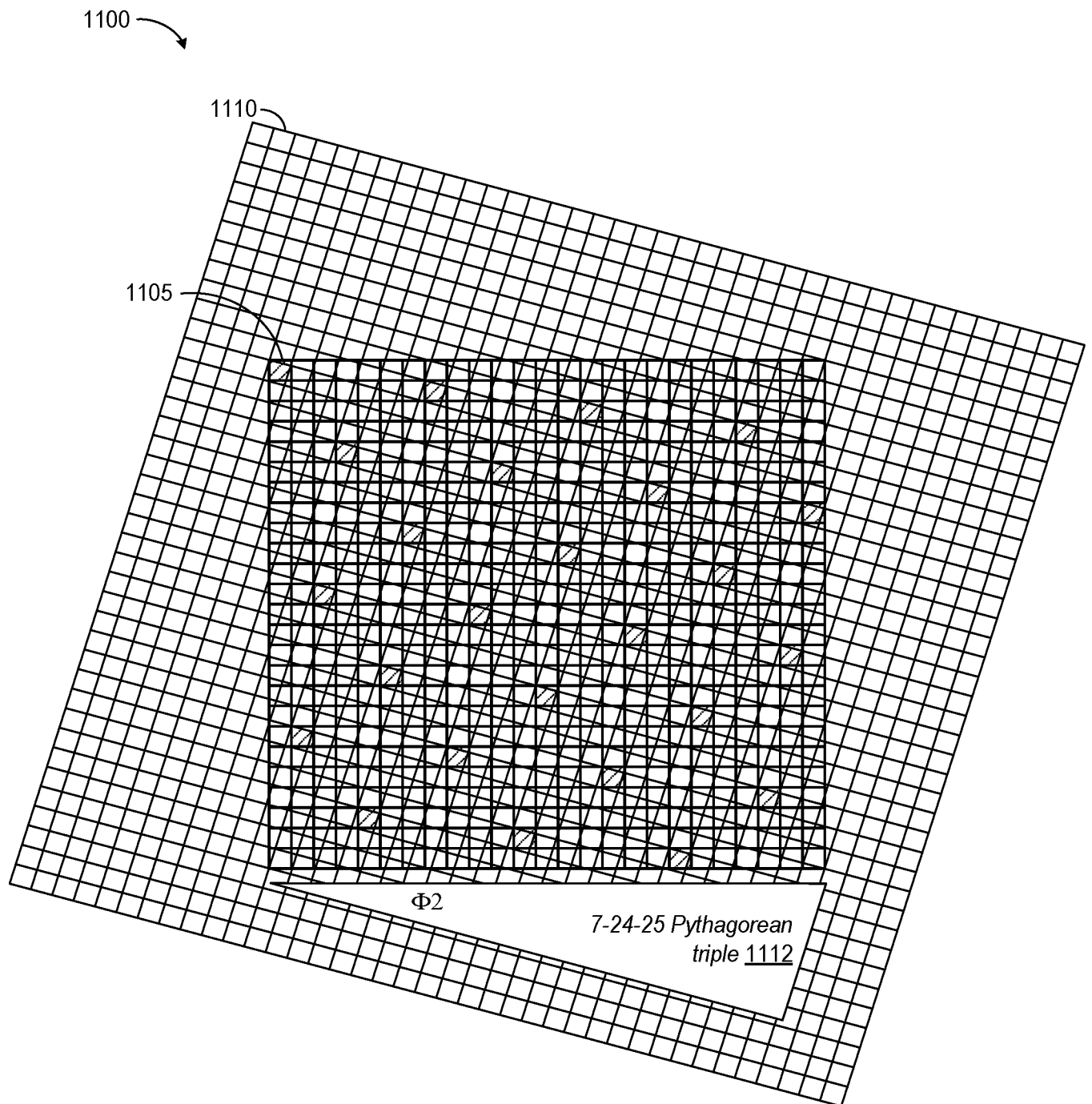


FIG. 11

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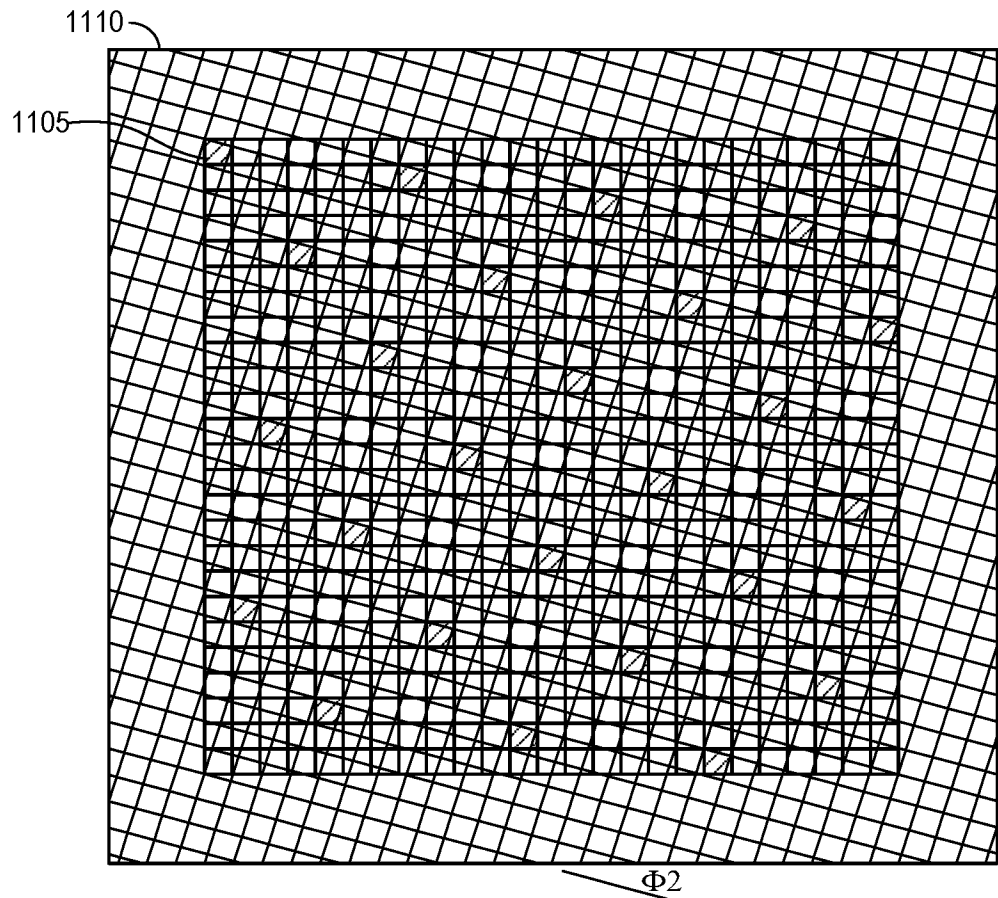


FIG. 12

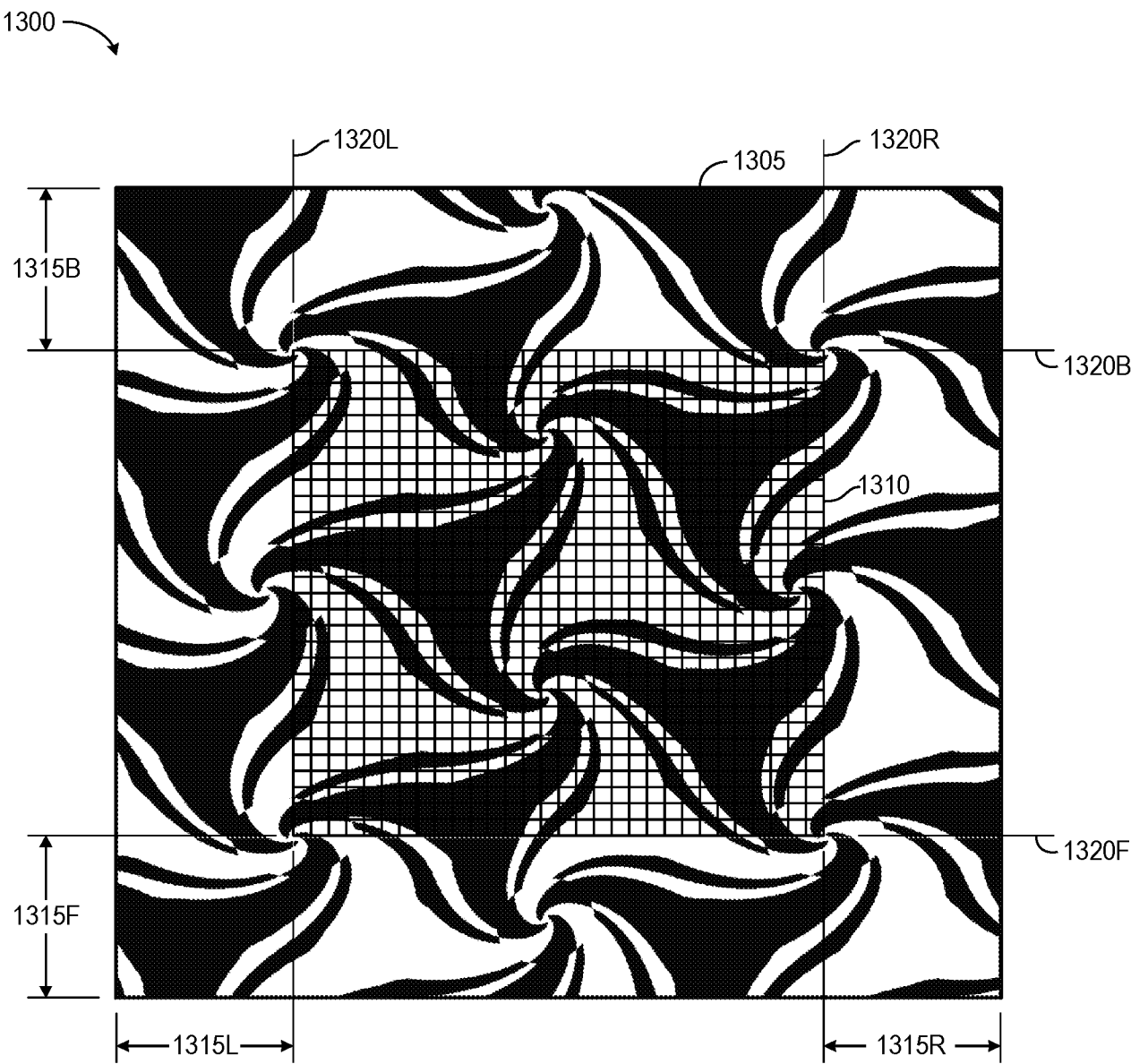


FIG. 13

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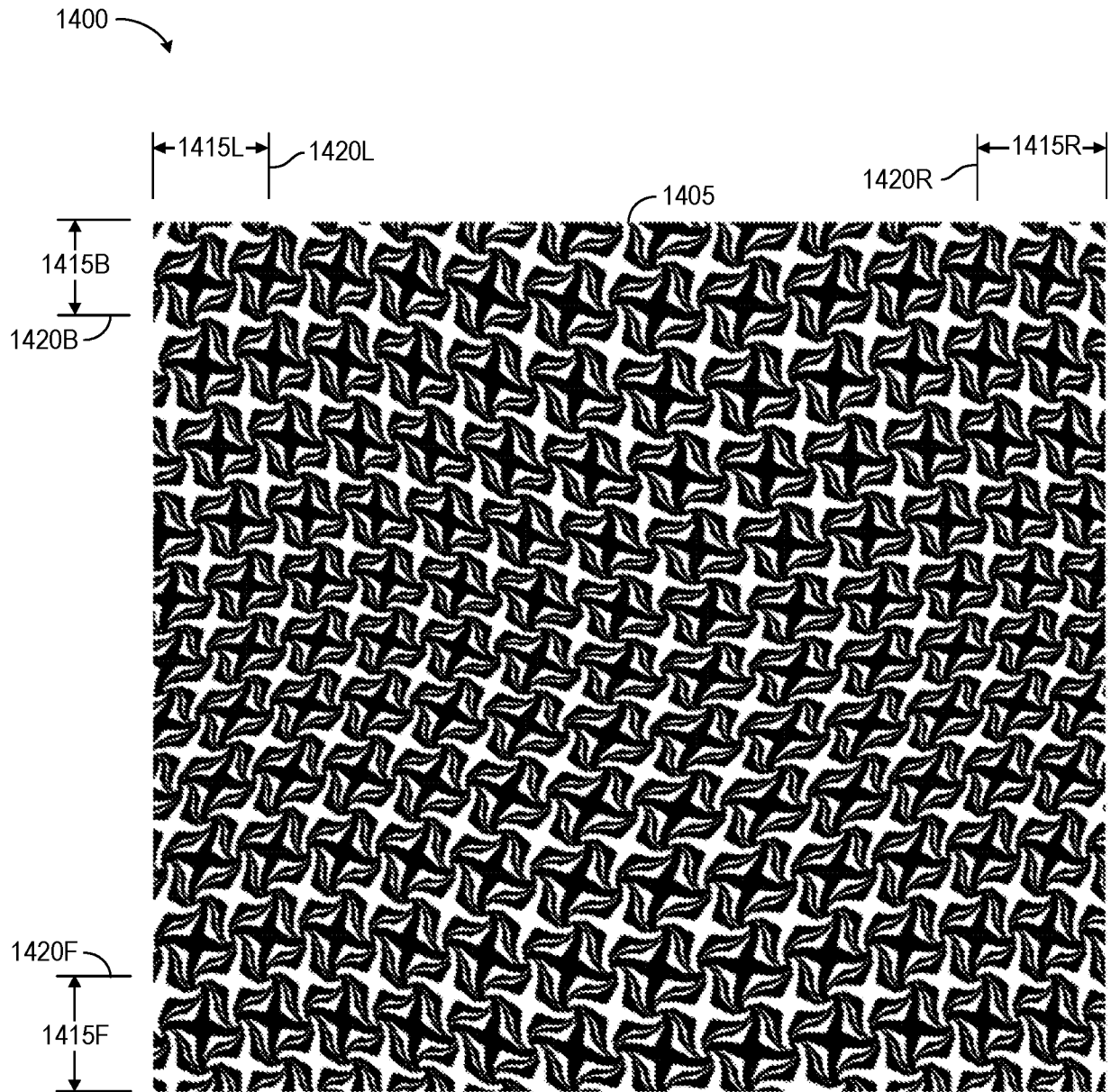


FIG. 14

INTERNATIONAL SEARCH REPORT

International application No.

PCT/US 16/60250

A. CLASSIFICATION OF SUBJECT MATTER

IPC(8) - G02B 5/18 (2016.01)

CPC - G02B 5/1871; G02B 26/10; H04N 5/2254; H04N 5/23229; G02F 1/29

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC(8): G02B 5/18 (2016.01)

CPC: G02B 5/1871; G02B 26/10; H04N 5/2254; H04N 5/23229; G02F 1/29

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

IPC(8): G02B 5/18 (2016.01)

CPC: G02B 5/1871; G02B 26/10; H04N 5/2254; H04N 5/23229; G02F 1/29; USPC: 385/10, 14; 250/550

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

Patbase, Google Web, Google Scholar Search terms used: Pixel, array, camera, imager, ccd, cmos, phase, grating, subgrating, larger, wider, longer, bigger, encompass, surround, enclose, circumscribe, overhang, frame, beyond, further, edge, angle, tilt, rotate, coprime, modulo, center, centre, coordinate, relate, reference

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 2013/0202081 A1 (ROSSI) 08 August 2013 (08.08.2013), para [0070], [0074], [0077], [0135], [0153], [0170], [0175], [0185], [0187]	1-3, 7, 8
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Y		9-14
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A		4-6, 15-22
Y	US 2015/0293018 A1 (STORK et al.) 15 October 2015 (15.10.2015), para [0048], [0053], [0055], [0058]-[0060], [0071], [0077], [0109], [0111]	9, 10
--		-----
A		15-22
Y	US 2015/0101002 A1 (YAMASHITA) 09 April 2015 (09.04.2015), para [0249]	11, 12
Y	US 2014/0185746 A1 (BATURIN et al.) 03 July 2014 (03.07.2014), para [0061], [0064]	13, 14
A	US 2004/0109068 A1 (MITSUNAGA et al.) 10 June 2004 (10.06.2004), para [0332], [0341], [0390]	15-22

☐ Further documents are listed in the continuation of Box C.

* Special categories of cited documents:

"A" document defining the general state of the art which is not considered to be of particular relevance

"E" earlier application or patent but published on or after the international filing date

"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)

"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art

"&" document member of the same patent family

Date of the actual completion of the international search

16 January 2017

Date of mailing of the international search report

03 FEB 2017

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Facsimile No. 571-273-8300

Authorized officer:

Lee W. Young

PCT Helpdesk: 571-272-4300
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